

**TC74HC85AP, TC74HC85AF, TC74HC85AFN****4 - BIT MAGNITUDE COMPARATOR**

The TC74HC85A is a high speed CMOS 4 BIT MAGNITUDE COMPARATOR fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

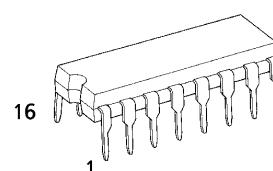
The TC74HC85A compares two 4-bit words applied to inputs A0 - A3 and B0 - B3, and provides a high voltage level on one of three outputs : A>B, A<B, or A=B.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

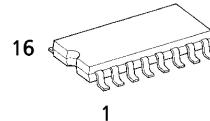
**FEATURES :**

- High Speed..... $t_{pd} = 22\text{ns}$  (typ.) at  $V_{CC} = 5\text{V}$
- Low Power Dissipation..... $I_{CC} = 4\mu\text{A}$ (Max.) at  $T_a = 25^\circ\text{C}$
- High Noise Immunity..... $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (Min.)
- Output Drive Capability..... 10 LSTTL Loads
- Symmetrical Output Impedance...  $|I_{OH}| = I_{OL} = 4\text{mA}$  (Min.)
- Balanced Propagation Delays..... $t_{PLH} \approx t_{PHL}$
- Wide Operating Voltage Range....  $V_{CC}$  (opr.) = 2V~6V
- Pin and Function Compatible with 74LS85

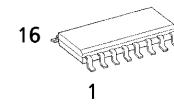
(Note) The JEDEC SOP (FN) is not available in Japan.



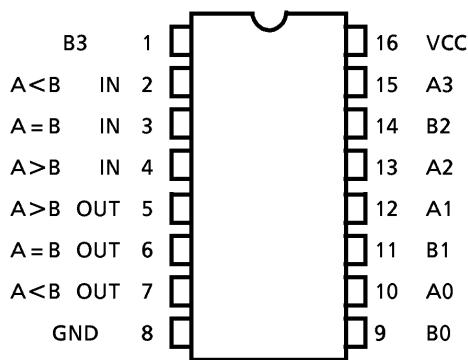
P (DIP16-P-300-2.54A)  
Weight : 1.00g (Typ.)



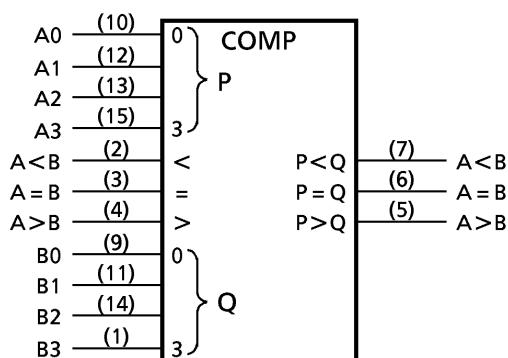
F (SOP16-P-300-1.27)  
Weight : 0.18g (Typ.)



FN (SOL16-P-150-1.27)  
Weight : 0.13g (Typ.)

**PIN ASSIGNMENT**

(TOP VIEW)

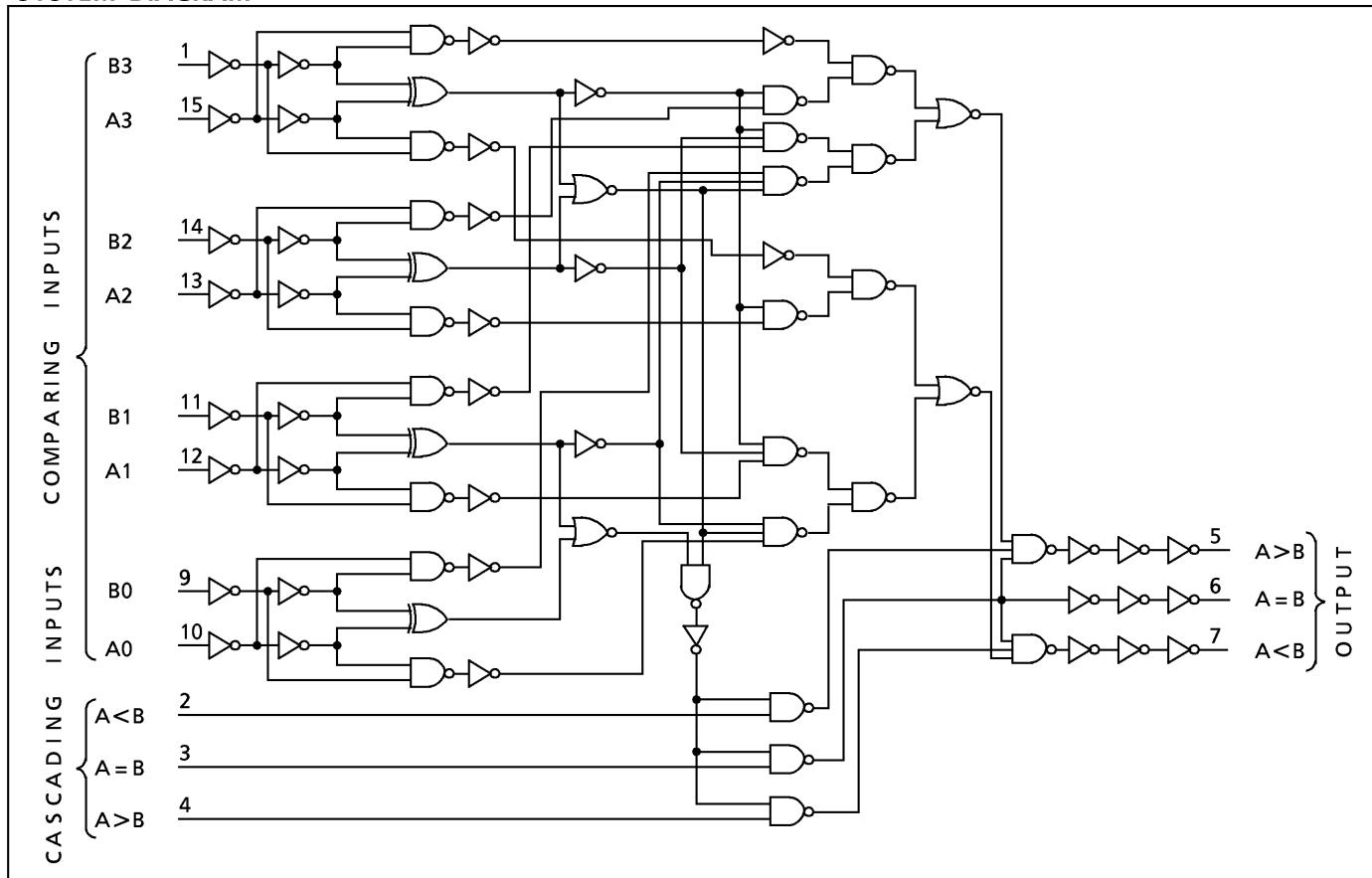
**IEC LOGIC SYMBOL**

## TRUTH TABLE

COMPARING INPUT				CASCADED INPUT			OUTPUT		
	A>B	A<B	A=B	A>B	A<B	A=B	A>B	A<B	A=B
A3>B3	X	X	X	X	X	X	H	L	L
A3=B3	A2>B2	X	X	X	X	X	H	L	L
A3=B3	A2=B2	A1>B1	X	X	X	X	H	L	L
A3=B3	A2=B2	A1=B1	A0>B0	X	X	X	H	L	L
A3=B3 , A2=B2 , A1=B1 , A0=B0				L	L	L	H	H	L
				X	X	H	L	H	H
				L	L	L	L	L	L
				H	H	L	H	L	L
				H	H	L	L	L	L
A3=B3	A2=B2	A1=B1	A0<B0	X	X	X	L	H	L
A3=B3	A2=B2	A1<B1	X	X	X	X	L	H	L
A3=B3	A2<B2	X	X	X	X	X	L	H	L
A3<B3	X	X	X	X	X	X	L	H	L

X : Don't Care

## SYSTEM DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	$V_{CC}$	-0.5~7	V
DC Input Voltage	$V_{IN}$	-0.5~ $V_{CC}$ + 0.5	V
DC Output Voltage	$V_{OUT}$	-0.5~ $V_{CC}$ + 0.5	V
Input Diode Current	$I_{IK}$	$\pm 20$	mA
Output Diode Current	$I_{OK}$	$\pm 20$	mA
DC Output Current	$I_{OUT}$	$\pm 25$	mA
DC $V_{CC}$ / Ground Current	$I_{CC}$	$\pm 50$	mA
Power Dissipation	$P_D$	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	$T_{STG}$	-65~150	°C

\*500mW in the range of  $T_a = -40^{\circ}\text{C} \sim 65^{\circ}\text{C}$ . From  $T_a = 65^{\circ}\text{C}$  to  $85^{\circ}\text{C}$  a derating factor of  $-10\text{mW}/^{\circ}\text{C}$  shall be applied until 300mW.

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	$V_{CC}$	2~6	V
Input Voltage	$V_{IN}$	0~ $V_{CC}$	V
Output Voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating Temperature	$T_{opr}$	-40~85	°C
Input Rise and Fall Time	$t_r, t_f$	0~1000 ( $V_{CC} = 2.0\text{V}$ ) 0~500 ( $V_{CC} = 4.5\text{V}$ ) 0~400 ( $V_{CC} = 6.0\text{V}$ )	ns

## DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}$ (V)	Ta = 25°C			Ta = -40~85°C		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
High - Level Input Voltage	$V_{IH}$		2.0 4.5 6.0	1.50 3.15 4.20	— — —	— — —	1.50 3.15 4.20	— — —	V
Low - Level Input Voltage	$V_{IL}$		2.0 4.5 6.0	— — —	— — —	0.50 1.35 1.80	— — —	0.50 1.35 1.80	V
High - Level Output Voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20\mu\text{A}$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	— — —	1.9 4.4 5.9	V
			$I_{OH} = -4\text{ mA}$ $I_{OH} = -5.2\text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	— —	4.13 5.63	
Low - Level Output Voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20\mu\text{A}$	2.0 4.5 6.0	— — —	0.0 0.0 0.0	0.1 0.1 0.1	— — —	V
			$I_{OL} = 4\text{ mA}$ $I_{OL} = 5.2\text{ mA}$	4.5 6.0	— —	0.17 0.18	0.26 0.26	— —	
Input Leakage Current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	$\pm 0.1$	—	$\pm 1.0$	$\mu\text{A}$
Quiescent Supply Current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	4.0	—	40.0	

AC ELECTRICAL CHARACTERISTICS ( $C_L = 15\text{pF}$ ,  $V_{CC} = 5\text{V}$ ,  $T_a = 25^\circ\text{C}$ , Input  $t_r = t_f = 6\text{ns}$ )

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition Time	$t_{TLH}$ $t_{THL}$		—	4	8	ns
Propagation Delay Time (A, B-OUT)	$t_{pLH}$ $t_{pHL}$		—	22	34	
Propagation Delay Time (CASCADE- OUT)	$t_{pLH}$ $t_{pHL}$		—	10	18	

AC ELECTRICAL CHARACTERISTICS ( $C_L = 50\text{pF}$ , Input  $t_r = t_f = 6\text{ns}$ )

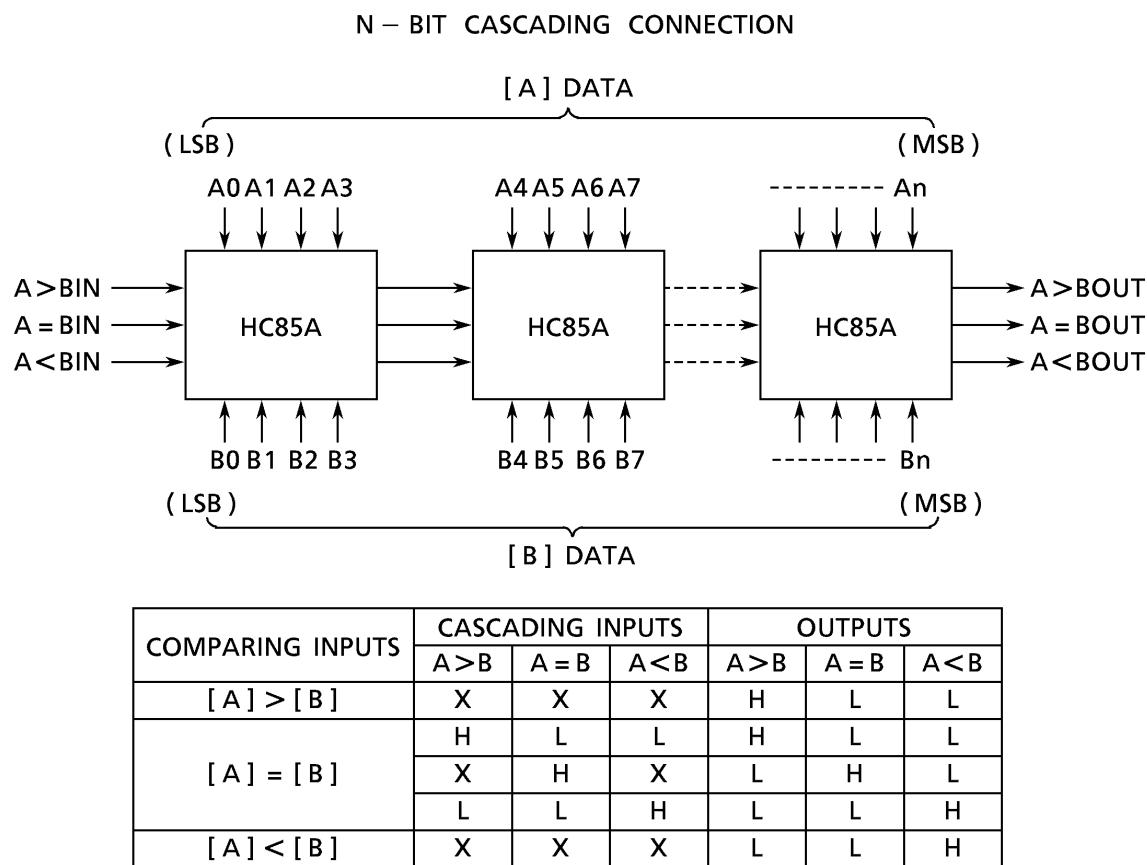
PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}$ (V)	$T_a = 25^\circ\text{C}$		$T_a = -40\text{--}85^\circ\text{C}$		UNIT
				MIN.	TYP.	MAX.	MIN.	
Output Transition Time	$t_{TLH}$ $t_{THL}$		2.0	—	30	75	—	95
			4.5	—	8	15	—	19
			6.0	—	7	13	—	16
Propagation Delay Time (A, B-OUT)	$t_{pLH}$ $t_{pHL}$		2.0	—	90	195	—	245
			4.5	—	26	39	—	49
			6.0	—	22	33	—	42
Propagation Delay Time (CASCADE- OUT)	$t_{pLH}$ $t_{pHL}$		2.0	—	40	110	—	140
			4.5	—	13	22	—	28
			6.0	—	11	19	—	24
Input Capacitance	$C_{IN}$		—	5	10	—	10	pF
Power Dissipation Capacitance	$C_{PD}$ (1)		—	25	—	—	—	

Note (1)  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

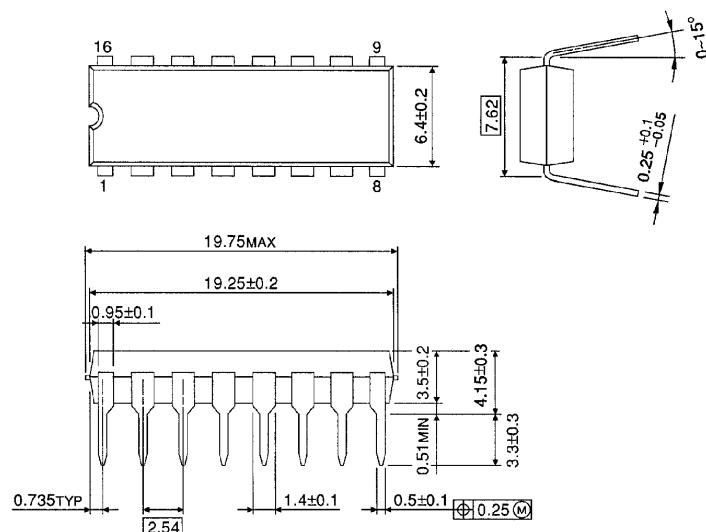
$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## TYPICAL APPLICATION



## DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

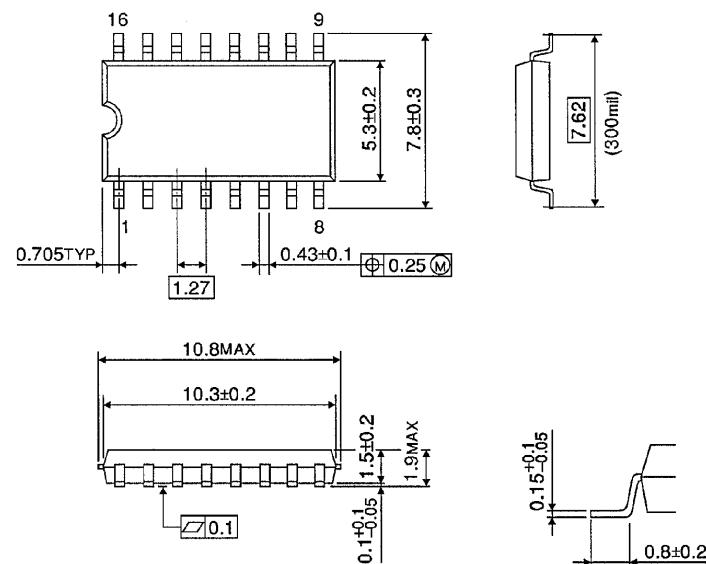
Unit in mm



Weight : 1.00g (Typ.)

## SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

Unit in mm

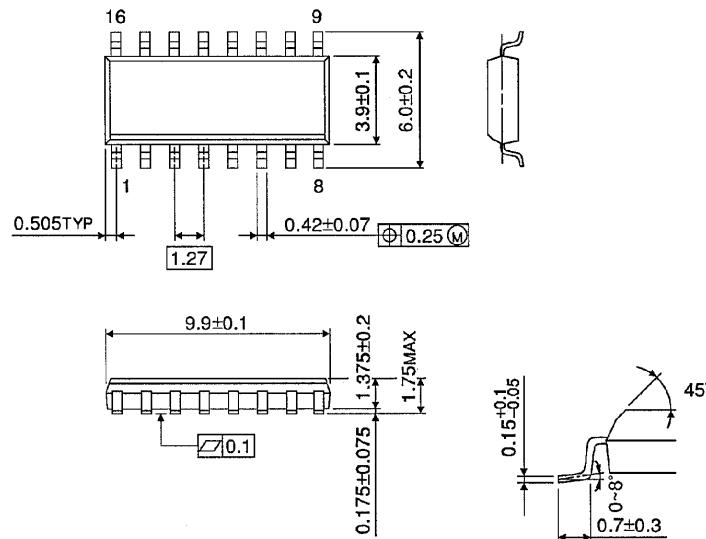


Weight : 0.18g (Typ.)

## SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)

Unit in mm

(Note) This package is not available in Japan.



Weight : 0.13g (Typ.)

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000707EBA

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